

Resource Summary Report

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JEOL: 2100F Transmission Electron Microscope

RRID:SCR_020155

Type: Tool

Proper Citation

JEOL: 2100F Transmission Electron Microscope (RRID:SCR_020155)

Resource Information

URL: <https://www.jeol.co.jp/en/products/detail/JEM-2100F.html>

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Description: JEM-2100F is a multipurpose, 200 kV FE (Field Emission) analytical electron microscope. Variety of versions is provided to adapt user's purposes. The FE electron gun (FEG) produces highly stable and bright electron probe that is never achieved with conventional thermionic electron gun. This feature is essential for ultrahigh resolution in scanning transmission microscopy and in an analysis of a nano-scaled sample. Various analytical instruments and/or cameras such as EDS (Energy Dispersive X-ray Spectrometer) or EELS (electron energy loss spectrometer) or CCD cameras are ready for integration with a PC system of the microscope control.

Resource Type: instrument resource

Keywords: JEOL, Transmission Electron Microscope, Instrument Equipment, USEDit

Availability: Commercially available

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/main/PDF/SCR_020155.pdf

Resource Name: JEOL: 2100F Transmission Electron Microscope

Resource ID: SCR_020155

Alternate IDs: Model_Number_2100F

Record Creation Time: 20220129T080348+0000

Record Last Update: 20260801T190652+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: 2100F Transmission Electron Microscope.

No alerts have been found for JEOL: 2100F Transmission Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.